


<b>Search Notes</b>  	<b>Application/Control No.</b>  10659593	<b>Applicant(s)/Patent Under Reexamination</b>  LEE, BAEK-WOON
	<b>Examiner</b>  Sherman, Stephen G	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
345	88,600,603-605,613,87-102	11/29/2006	SS
349	56,82,84,109,143		

SEARCH NOTES		
Search Notes	Date	Examiner
See attached search history		
Search Updated	11/29/2006	SS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner